IMS3TW’11 will continue to address the traditional technology spectrum of analog, mixed-signal, and RF testing, but with increased attention to all aspects of current design complexity (e.g., parametric variability, power consumption, temperature effects). In this year’s program, in addition to keynote speeches, two special sessions have been organized:

**Current Industrial Practices for Analog/Mixed-Signal/RF IC Test**
Organizer: TM Mak, Intel, USA
- Elida de-Obaldia, Texas Instruments, USA
- Bryan Casper, Intel, USA
- Michael Laisne, Qualcomm, USA

**Lab-on-Chip Test Issues**
Organizer: A. Simonian, Auburn University, NSF Bio-sensors Program Director, USA
- Holger Schmidt, UC Santa Cruz, USA
- Ali Adibi, Georgia Tech, USA
- M.A. Miled and M. Sawan, École Polytechnique de Montréal, Canada

**Social Program:** Santa Barbara is known for its world-class wine and vineyards. In this year’s social program, we will visit two local wineries in the Santa Ynez Valley.

Prospective authors are invited to submit papers on the topics of interest listed below. Submissions should be via the workshop web-site and consist of either an extended summary of at least 750 words or a full paper. The accepted papers will be published in an IEEE Computer Society Proceedings available on the IEEE digital library (EXPLORE). Selected papers from the workshop will be invited for submission to a special issue of Journal of Electronic Testing (JETTA).

**Primary Topics of Interest include:**
- Test & Design for (on/off-line) Test Verification & Design for Verification
- Reliability & Design for Reliability
- Fault/Error Modelling & Simulation
- Fault Tolerance

**Pertaining to the following systems or underlying technologies:**
- Analog/Mixed-Signal Circuits
- Biomedical Circuits & Systems
- RF & Wirelessly Controlled Devices
- Optoelectronics & Photonics
- Drug Delivery Microsystems

**Key Dates**
- Submission deadline: February 21, 2011
- Notification of acceptance: March 21, 2011
- Camera-ready full papers: April 21, 2011